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Application Specific Discretes A.S.D.™

RBO40-40G/T REVERSED BATTERY AND

OVERVOLTAGE PROTECTION

FEATURES

- PROTECTION AGAINST "LOAD DUMP" PULSE
- 40A DIODE TO GUARD AGAINST BATTERY REVERSAL
- MONOLITHIC STRUCTURE FOR GREATER RELIABILITY
- BREAKDOWN VOLTAGE : 24 V min.
- CLAMPING VOLTAGE : ± 40 V max.
- COMPLIANT WITH ISO / DTR 7637

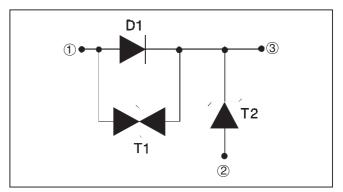
DESCRIPTION

Designed to protect against battery reversal and load dump overvoltages in automotive applications, this monolithic component offers multiple functions in the same package :

- D1 : reversed battery protection
- T1 : clamping against negative overvoltages
- T2 : Transil function against "load dump" effect.

<image>

FUNCTIONAL DIAGRAM



TM : TRANSIL and ASD are trademarks of STMicroelectronics.

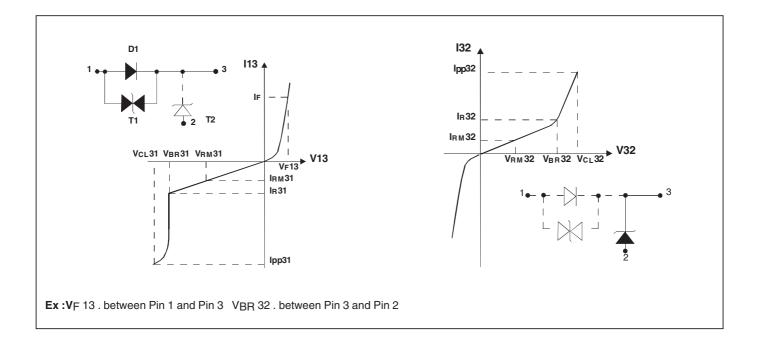
ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit	
I _{FSM}	Non repetitive surge peak forward current (Diode D1)	e surge peak forward current tp = 10 ms		
lF	DC forward current (Diode D1)	40	A	
V _{PP}	Peak load dump voltage (see note 1and 2) 5 pulses (1 minute between each pulse)	80	V	
P _{PP}	Peak pulse power between Input and Output (Transil T1) Tj initial = 25°C	1500	W	
T _{stg} /Tj	Storage and operating junction temperature range	- 40 to + 150	°C	
TL	Maximum lead temperature for soldering during at 4.5mm from case for TO220-AB	260	°C	

Note 1 : for a surge greater than the maximum value, the device will fail in short-circuit. **Note 2 :** see Load Dump curves.

THERMAL RESISTANCE

Symbol	Parameter		Value	Unit
Rth (j-c)	Junction to case	RBO40-40G RBO40-40T	1.0 1.0	°C/W
Rth (j-a)	Junction to ambient	RBO40-40T	60	°C/W



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Symbol	Parameter	
V _{RM31} /V _{RM32}	Stand-off voltage Transil T1 / Transil T2.	
V _{BR31} /V _{BR32}	reakdown voltage Transil T1 / Transil T2.	
I _{R31} /I _{R32}	eakage current Transil T1 / Transil T2.	
V _{CL31} /V _{CL32}	Clamping voltage Transil T1 / Transil T2.	
V _{F13}	Forward voltage drop Diode D1.	
I _{PP}	Peak pulse current.	
αΤ	Temperature coefficient of V _{BR} .	
C ₃₁ /C ₃₂	Capacitance Transil T1 / Transil T2.	
C ₁₃	Capacitance of Diode D1	

ELECTRICAL CHARACTERISTICS : DIODE D1 (- 40°C < T_{amb} < + 85°C)

Symbol	Test Conditions		l la it		
		Min.	Тур.	Max.	Unit
V _{F 13}	$I_F = 40 \text{ A}$			1.9	V
V _{F 13}	I _F = 20A			1.45	V
V _{F 13}	$I_F = 1 A$			1	V
V _{F 13}	I _F = 100 mA			0.95	V
C ₁₃	$F = 1MHz$ $V_{R} = 0 V$		3000		pF

ELECTRICAL CHARACTERISTICS : TRANSIL T1 (- $40^{\circ}C < T_{amb} < + 85^{\circ}C$)

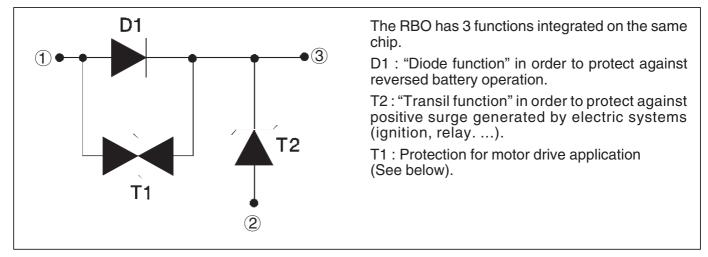
Symbol	Test Conditions			Value			
Symbol				Тур.	Max.	Unit	
V _{BR 31}	$I_{\rm R} = 1 \rm mA$		22		35	V	
V _{BR 31}	$I_R = 1 \text{ mA}, T_{amb} = 25^{\circ}C$		24		32	V	
I _{RM 31}	V _{RM} = 20 V				100	μA	
I _{RM 31}	$V_{RM} = 20 \text{ V}, \text{ T}_{amb} = 25^{\circ}\text{C}$				10	μA	
V _{CL 31}	I _{PP} = 37.5A, Tj initial = 25°C 10/1000μs				40	V	
αΤ	Temperature coefficient of VBR				9	10 ⁻⁴ /°C	
C 31	$F = 1MHz$ $V_R = 0 V$			3000		pF	

ELECTRICAL CHARACTERISTICS : TRANSIL T2 (- $40^{\circ}C < T_{amb} < + 85^{\circ}C$)

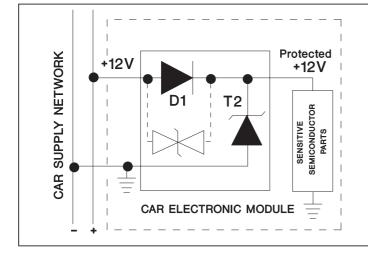
Symbol	Test Conditions		11			
Symbol	Test Conditions		Тур.	Max.	Unit	
V _{BR 32}	$I_{\rm R} = 1 \mathrm{mA}$	22		35	V	
V _{BR 32}	$I_R = 1 \text{ mA}, T_{amb} = 25^{\circ}\text{C}$	24		32	V	
I _{RM 32}	V _{RM} = 20 V			100	μA	
I _{RM 32}	$V_{RM} = 20 \text{ V}, \text{ T}_{amb} = 25^{\circ}\text{C}$			10	μA	
V _{CL 32}	$I_{PP} = 20 \text{ A} \text{ (note 1)}$			40	V	
αΤ	Temperature coefficient of V _{BR}			9	10 ⁻⁴ /°C	
C ₃₂	$F = 1MHz$ $V_R = 0 V$		8000		pF	

Note 1 : One pulse, see pulse definition in load dump test generator circuit.

PRODUCT DESCRIPTION

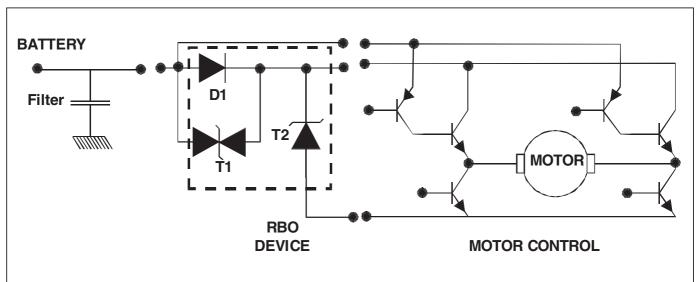


BASIC APPLICATION



* The monolithic multi-function protection (RBO) has been developed to protect sensitive semiconductors in car electronic modules against both overvoltage and battery reverse.

* In addition, the RBO circuit prevents overvoltages generated by the module from affecting the car supply network.



MOTOR DRIVER APPLICATION

In this application, one half of the motor drive circuit is supplied through the "RBO" and is thus protected as per its basic function application.

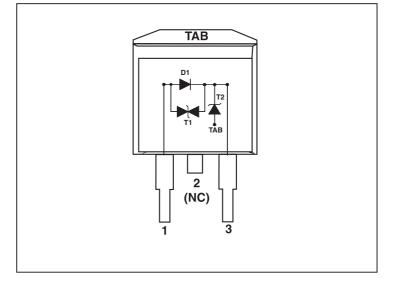
The second part is connected directly to the "car supply network" and is protected as follows :

- For positive surges : T2 (clamping phase) and D1 in forward-biased.
- For negative surges : T1 (clamping phase) and T2 in forward-biased.

/

PINOUT configuration in D^2PAK:

- Input (1): Pin 1
- Output (3): Pin 3
- Gnd (2): Connected to base Tab
- Marking : Logo, date code, RBO40-40G

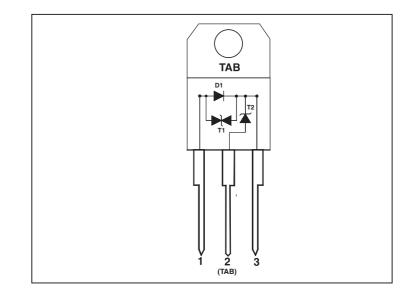


PINOUT configuration in TO220AB :

- Input (1): Pin 1
- Output (3): Pin 3

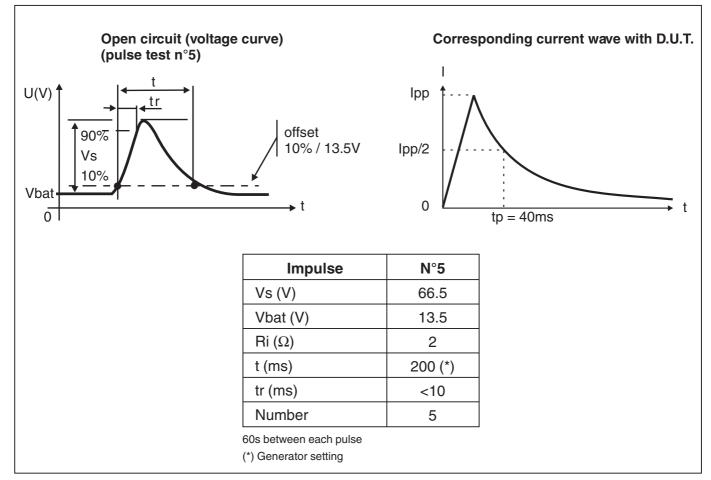
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- GND (2): Connected to base Tab
- Marking : Logo, date code, RBO40-40T

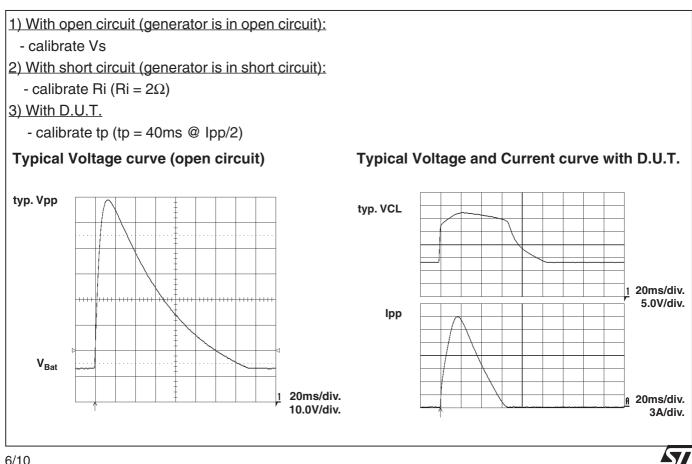


RBO40-40G / RBO40-40T

LOAD DUMP TEST GENERATOR CIRCUIT (SCHAFFNER NSG 506 C). Issued from ISO / DTR 7637.



CALIBRATION METHOD FOR SCHAFFNER NSG 506 C



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Fig. 1 : Peak pulse power versus exponential pulse duration (Tj initial = 85° C).

Fig. 2-1 : Clamping voltage versus peak pulse current (Tj initial = 85° C).

Exponential waveform tp = 40 ms and tp = 1 ms (TRANSIL T2).

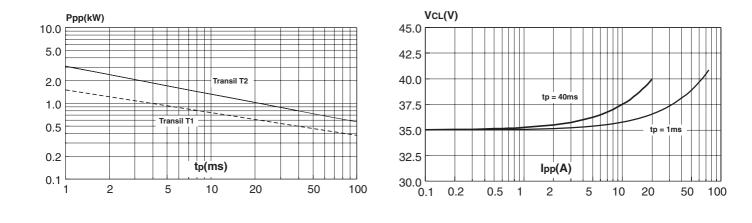


Fig. 2-2 : Clamping voltage versus peak pulse current (Tj initial = 85° C).

Exponential waveform tp = 1 ms and tp = 20 μ s (TRANSIL T1).

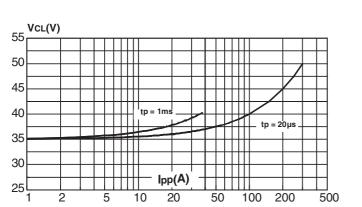


Fig. 3 : Relative variation of peak pulse power versus junction temperature.

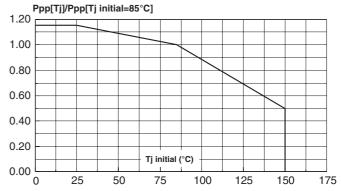


Fig. 4 : Relative variation of thermal impedance junction to case versus pulse duration.

Zth(j-c)/Rth(j-c)

Fig. 5-1 : Peak forward voltage drop versus peak forward current (typical values) - (TRANSIL T2).

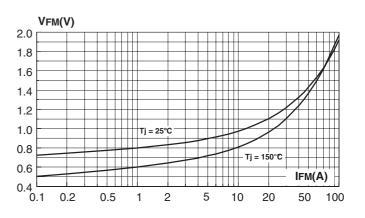
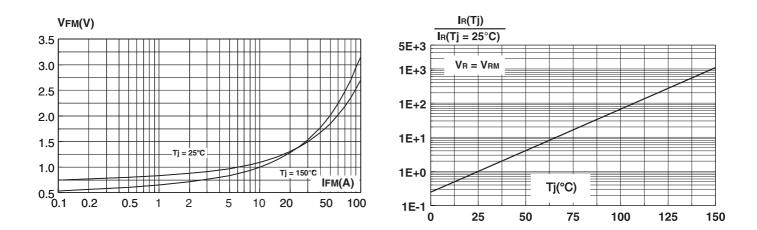


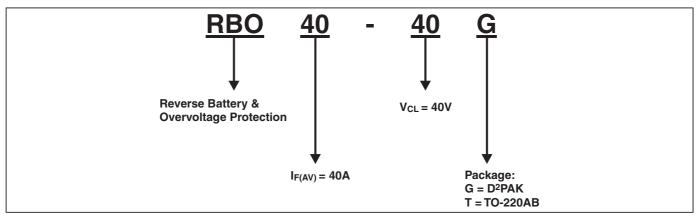
Fig. 5-2 : Peak forward voltage drop versus peak forward current (typical values) - (DIODE D1).

Fig. 6 : Relative variation of leakage current versus junction temperature.

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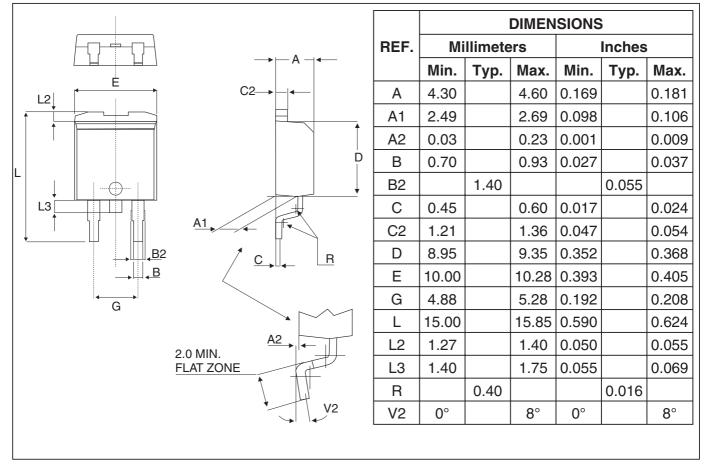


ORDERING INFORMATION

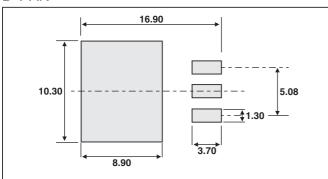


PACKAGE MECHANICAL DATA

D²PAK Plastic



FOOT-PRINT (in millimeters) D²PAK



PACKAGE MECHANICAL DATA TO-220AB Plastic

			DIMENSIONS					
		REF.	. Millimeters			Inches		
B	b2		Min.	Тур.	Max.	Min.	Тур.	Max.
		A	15.20		15.90	0.598		0.625
		a1		3.75			0.147	
		a2	13.00		14.00	0.511		0.551
		В	10.00		10.40	0.393		0.409
A		b1	0.61		0.88	0.024		0.034
		b2	1.23		1.32	0.048		0.051
14		С	4.40		4.60	0.173		0.181
$\square \square $		c1	0.49		0.70	0.019		0.027
a1	c2	c2	2.40		2.72	0.094		0.107
·────────────────────────────────────		е	2.40		2.70	0.094		0.106
		F	6.20		6.60	0.244		0.259
		I	3.75		3.85	0.147		0.151
		14	15.80	16.40	16.80	0.622	0.646	0.661
ΨΨΨ		L	2.65		2.95	0.104		0.116
<u>b1</u>		12	1.14		1.70	0.044		0.066
e	► <u></u> = <u>c1</u>	13	1.14		1.70	0.044		0.066
		Μ		2.60			0.102	

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